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CORRIGENDUM

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Corrigendum: "Reliability of piezoelectric films for MEMS" [Jpn. J. Appl. Phys. 62, SM0802 (2023)]

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The numerical values in the last column in Table I should be corrected as follows. The reason for the correction is an authors' error in writing. For additional clarity, the range of E_B values measured are included.

Table I. Comparison of gradient and gradient free PZT films. ε_r is relative permittivity, P_r is remanent polarization, E_C is coercive field, E_i is imprint and E_B is electrical breakdown field. The imprint was measured after poling either field up or field down at 200 kV cm^{-1} for 30 min at 150 °C. The polarization measurements were performed by driving the bottom electrode and the observed positive shift of the polarization loop indicated an initial field down imprint in both films, albeit more pronounced in the gradient free case.

	ε_r	Tan δ	P_{r-}, P_{r+} (μC cm^{-2})	E_{c-}, E_{c+} (kV cm^{-1})	E_i initial and after poling field down/up (kV cm^{-1})	E_B field down/up (kV cm^{-1})
Gradient	1280	0.033	−15.3, 14.1	−20.3, 27.0	3.33, 9.43/−7.73	785 ± 16/818 ± 10
Gradient free	1470	0.035	−15.5, 9.0	−10.5, 28.5	8.9, 13.2/−3.25	793 ± 3/830 ± 15

This correction does not affect any other part of the article.